


<b>Search Notes</b>  	<b>Application/Control No.</b>  10559915	<b>Applicant(s)/Patent Under Reexamination</b>  RUIGROK ET AL.
	<b>Examiner</b>  Alain L Bashore	<b>Art Unit</b>  1792

SEARCHED			
Class	Subclass	Date	Examiner
427	547,	12-19-08	ab
29	603.08; 603.14	12-19-08	ab

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (attached)	12-18-08	ab
eDAN inventor search	12-18-08	ab
previous search updated	6-8-09	ab
EAST search (updated)	12/5/2009	ML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/M. C. L./ Examiner.Art Unit 1792	/Alain L Bashore/ Primary Examiner.Art Unit 1792
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